Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
08870762	DUFT ET AL.
Examiner	Art Unit
S. Devi, Ph.D.	1645

SEARCHED							
Class	Subclass	Date	Examiner				

SEARCH NOTES				
Search Notes	Date	Examiner		
Consultations with tQAS Witz & Wax. SPE Eyler & Stucker.	April, 08	SD		

	RCH		
Class	Subclass	Date	Examiner

U.S. Patent and Trademark Office Part of Paper No.: 200804